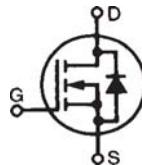


High Voltage Power MOSFET

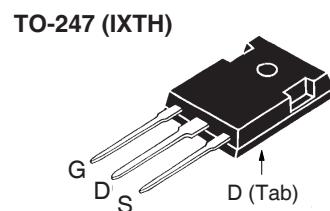
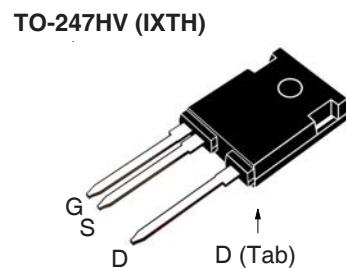
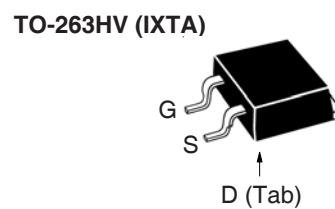
IXTA1N200P3HV
IXTH1N200P3HV
IXTH1N200P3

V_{DSS} = 2000V
I_{D25} = 1.0A
R_{DS(on)} ≤ 40Ω

N-Channel Enhancement Mode



Symbol	Test Conditions	Maximum Ratings	
V _{DSS}	T _J = 25°C to 150°C	2000	V
V _{DGR}	T _J = 25°C to 150°C, R _{GS} = 1MΩ	2000	V
V _{GSS}	Continuous	±20	V
V _{GSM}	Transient	±30	V
I _{D25}	T _C = 25°C	1.0	A
I _{D110}	T _C = 110°C	0.6	A
I _{DM}	T _C = 25°C, Pulse Width Limited by T _{JM}	3.0	A
P _D	T _C = 25°C	125	W
T _J		- 55 ... +150	°C
T _{JM}		150	°C
T _{stg}		- 55 ... +150	°C
T _L	Maximum Lead Temperature for Soldering	300	°C
T _{sold}	1.6 mm (0.062in.) from Case for 10s	260	°C
F _c	Mounting Force (TO-263HV)	10..65 / 22..14.6	N/lb
M _d	Mounting Torque (TO-247/HV)	1.13/10	Nm/lb.in
Weight	TO-263HV	2.5	g
	TO-247/HV	6.0	g



G = Gate D = Drain
S = Source Tab = Drain

Features

- High Blocking Voltage
- High Voltage Packages

Advantages

- Easy to Mount
- Space Savings
- High Power Density

Applications

- High Voltage Power Supplies
- Capacitor Discharge Applications
- Pulse Circuits
- Laser and X-Ray Generation Systems

Symbol	Test Conditions (T _J = 25°C, Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max.
BV _{DSS}	V _{GS} = 0V, I _D = 250μA	2000		V
V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250μA	2.0		4.0 V
I _{GSS}	V _{GS} = ±20V, V _{DS} = 0V			±100 nA
I _{DSS}	V _{DS} = V _{DSS} , V _{GS} = 0V T _J = 125°C			5 μA 100 μA
R _{DS(on)}	V _{GS} = 10V, I _D = 0.5A, Note 1			40 Ω

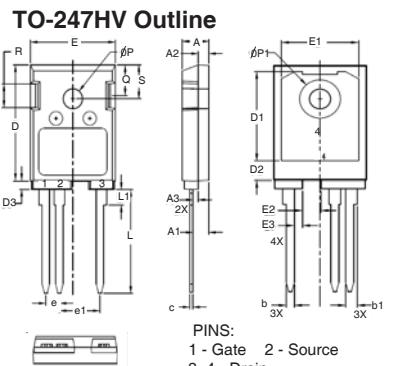
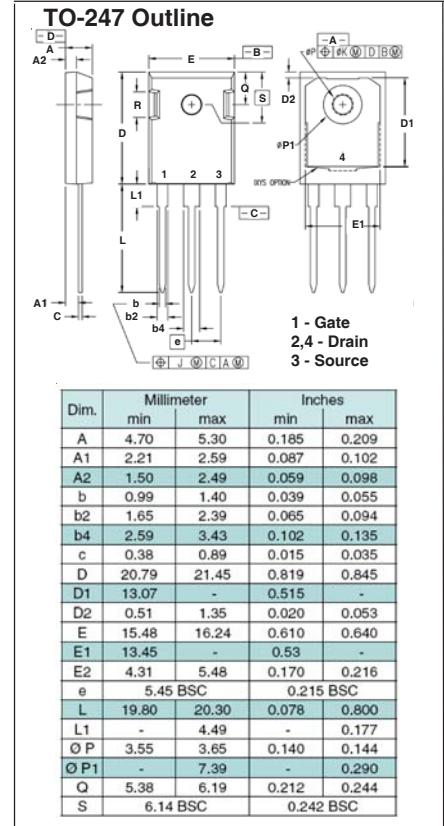
Symbol **Test Conditions**
 $(T_J = 25^\circ C, \text{ Unless Otherwise Specified})$
Characteristic Values
Min. **Typ.** **Max.**

g_{fs}	$V_{DS} = 50V, I_D = 0.5A$, Note 1	0.4	0.7	S
C_{iss} C_{oss} C_{rss}	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$	646	pF	
		50	pF	
		17	pF	
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	Resistive Switching Times $V_{GS} = 10V, V_{DS} = 1kV, I_D = 0.5 \cdot I_{D25}$ $R_G = 5\Omega$ (External)	16	ns	
		26	ns	
		37	ns	
		80	ns	
$Q_{g(on)}$ Q_{gs} Q_{gd}	$V_{GS} = 10V, V_{DS} = 1kV, I_D = 0.5 \cdot I_{D25}$	23.5	nC	
		3.1	nC	
		13.3	nC	
R_{thJC} R_{thCS}	TO-247	0.21	1.0 $^\circ C/W$ $^\circ C/W$	

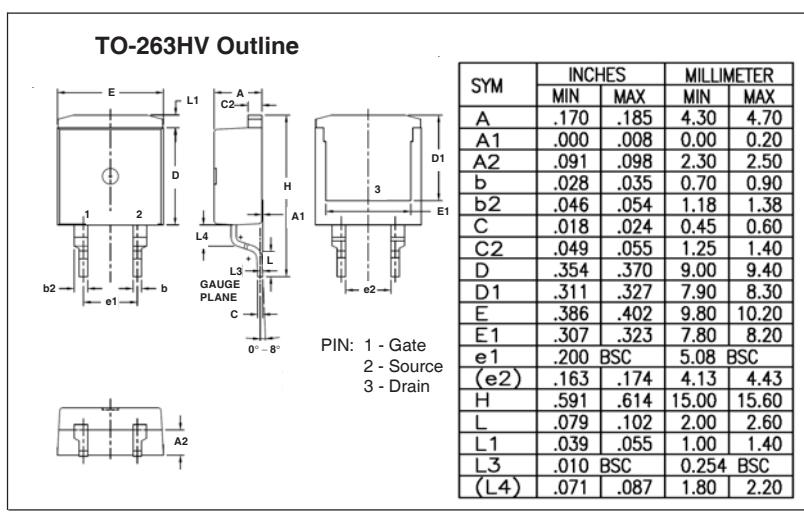
Source-Drain Diode
Symbol **Test Conditions**
 $(T_J = 25^\circ C, \text{ Unless Otherwise Specified})$
Characteristic Values
Min. **Typ.** **Max.**

I_s	$V_{GS} = 0V$		1	A
I_{sm}	Repetitive, Pulse Width Limited by T_{JM}		4	A
V_{SD}	$I_F = I_S, V_{GS} = 0V$, Note 1		1.5	V
t_{rr}	$I_F = 1A, -di/dt = 100A/\mu s, V_R = 100V$	2.3		μs

Note: 1. Pulse test, $t \leq 300\mu s$, duty cycle, $d \leq 2\%$.



SYM	INCHES		MILLIMETER	
	MIN	MAX	MIN	MAX
A	.170	.185	4.30	4.70
A1	.000	.008	0.00	0.20
A2	.091	.098	2.30	2.50
b	.028	.035	0.70	0.90
b2	.046	.054	1.18	1.38
C	.018	.024	0.45	0.60
C2	.049	.055	1.25	1.40
D	.354	.370	9.00	9.40
D1	.311	.327	7.90	8.30
E	.386	.402	9.80	10.20
E1	.307	.323	7.80	8.20
e1	.200 BSC		5.08 BSC	
(e2)	.163	.174	4.13	4.43
H	.591	.614	15.00	15.60
L	.079	.102	2.00	2.60
L1	.039	.055	1.00	1.40
L3	.010 BSC		0.254 BSC	
(L4)	.071	.087	1.80	2.20



IXYS Reserves the Right to Change Limits, Test Conditions, and Dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents: 4,835,592 4,931,844 5,049,961 5,237,481 6,162,665 6,404,065 B1 6,683,344 6,727,585 7,005,734 B2 7,157,338B2 4,860,072 5,017,508 5,063,307 5,381,025 6,259,123 B1 6,534,343 6,710,405 B2 6,759,692 7,063,975 B2 4,881,106 5,034,796 5,187,117 5,486,715 6,306,728 B1 6,583,505 6,710,463 6,771,478 B2 7,071,537

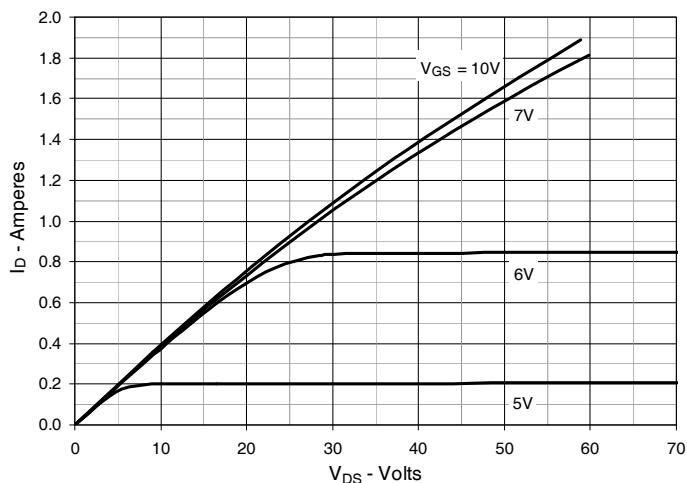
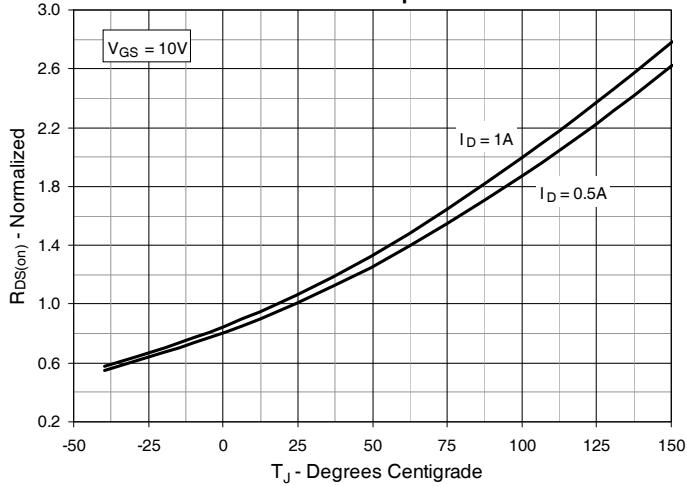
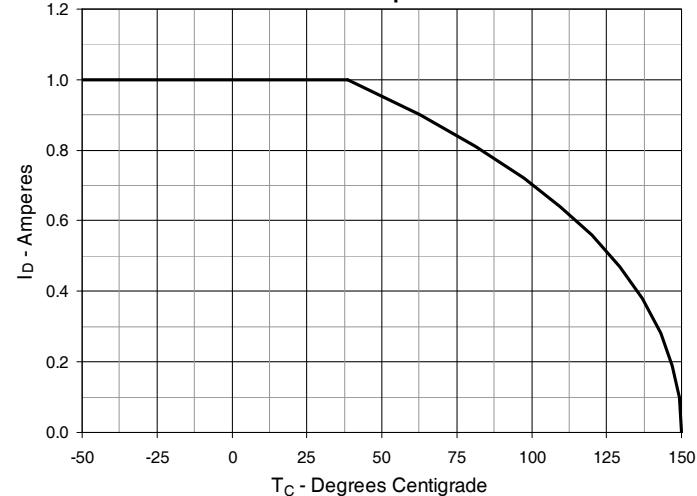
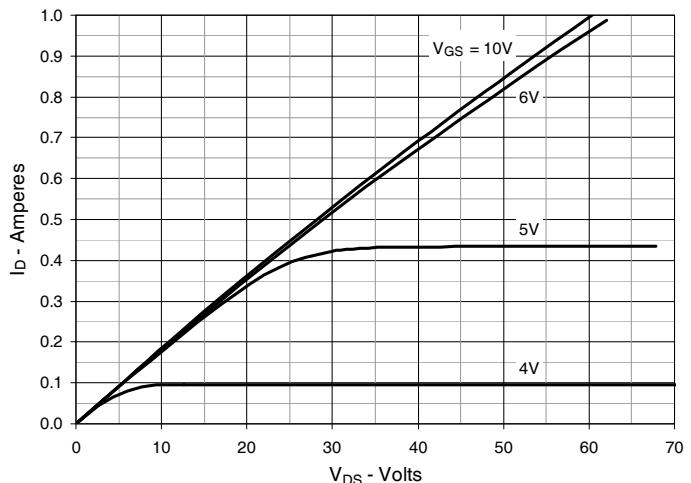
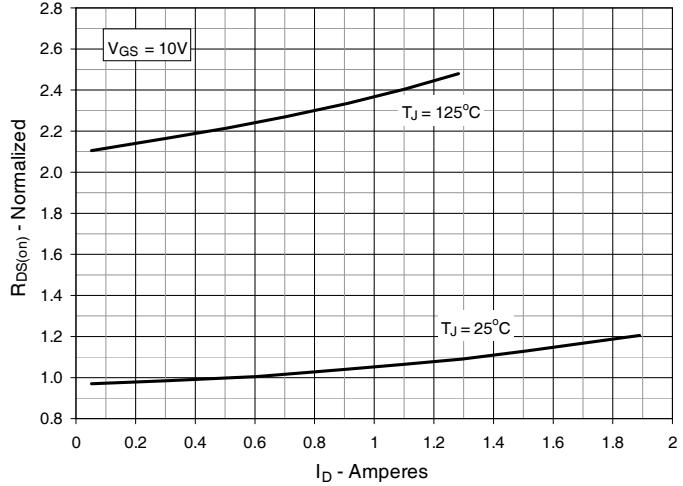
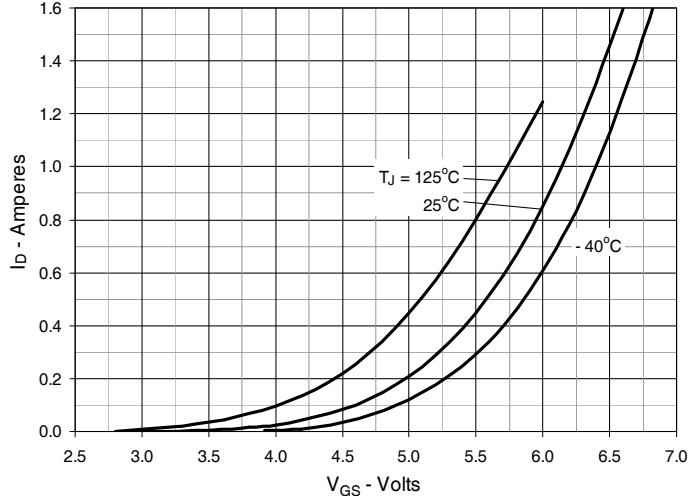
Fig. 1. Output Characteristics @ $T_J = 25^\circ\text{C}$

Fig. 3. $R_{DS(on)}$ Normalized to $I_D = 0.5\text{A}$ Value vs. Junction Temperature

Fig. 5. Maximum Drain Current vs. Case Temperature

Fig. 2. Output Characteristics @ $T_J = 125^\circ\text{C}$

Fig. 4. $R_{DS(on)}$ Normalized to $I_D = 0.5\text{A}$ Value vs. Drain Current

Fig. 6. Input Admittance


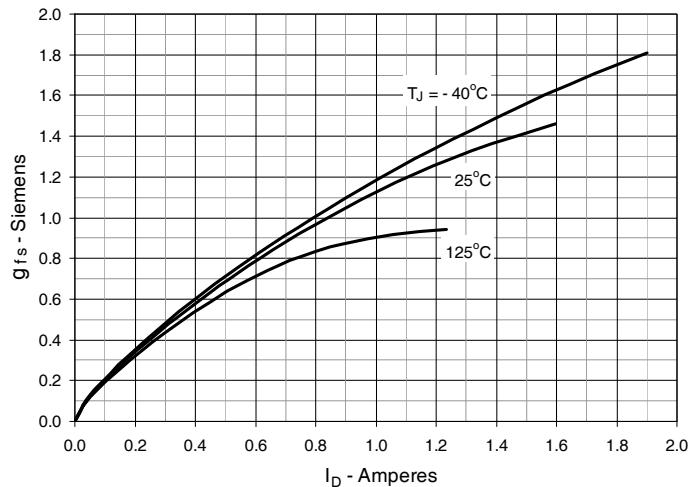
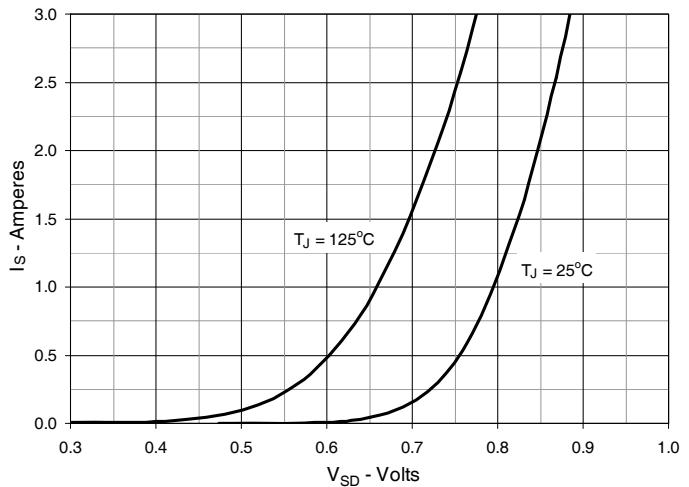
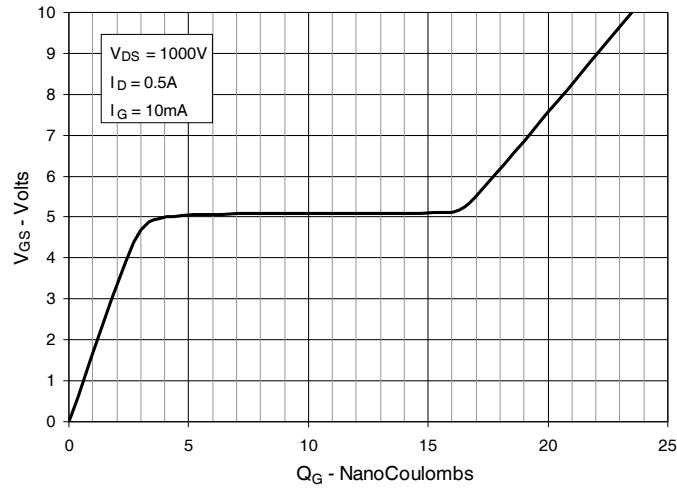
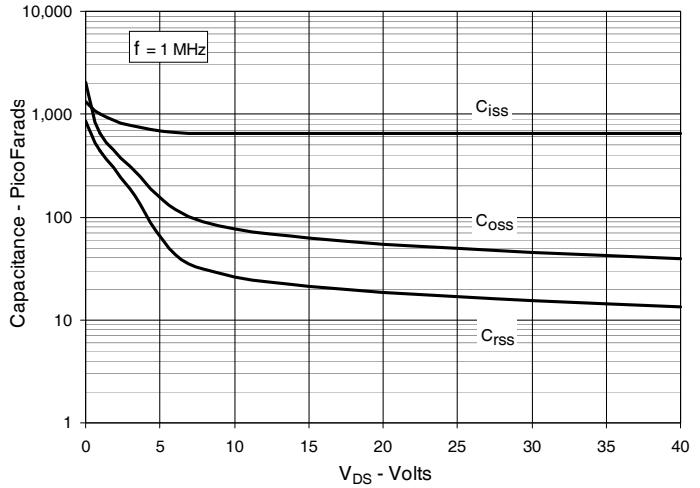
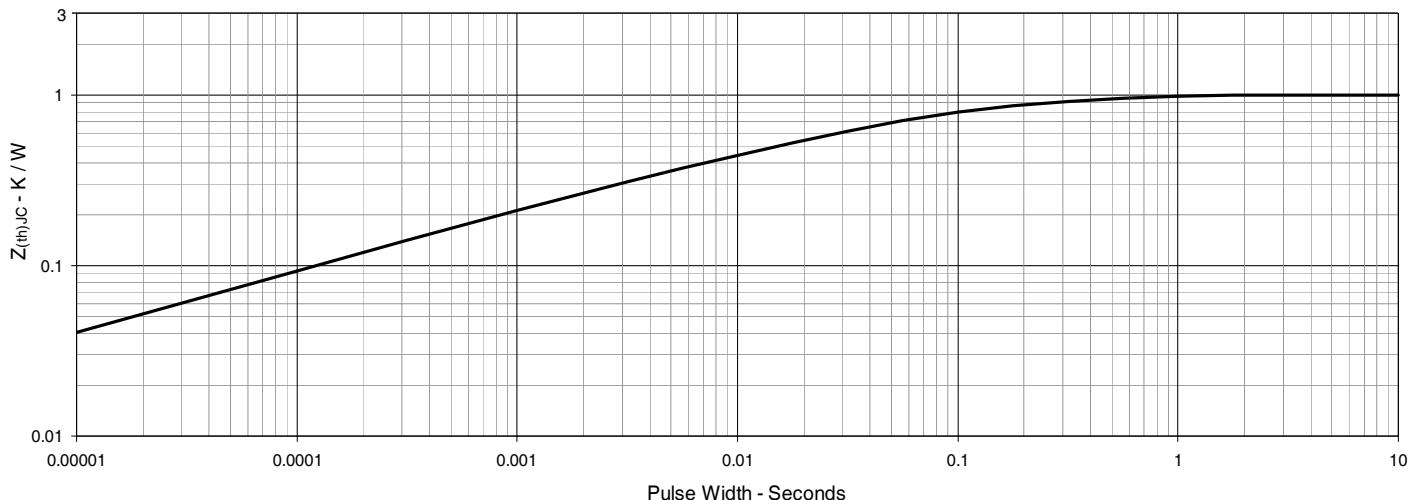
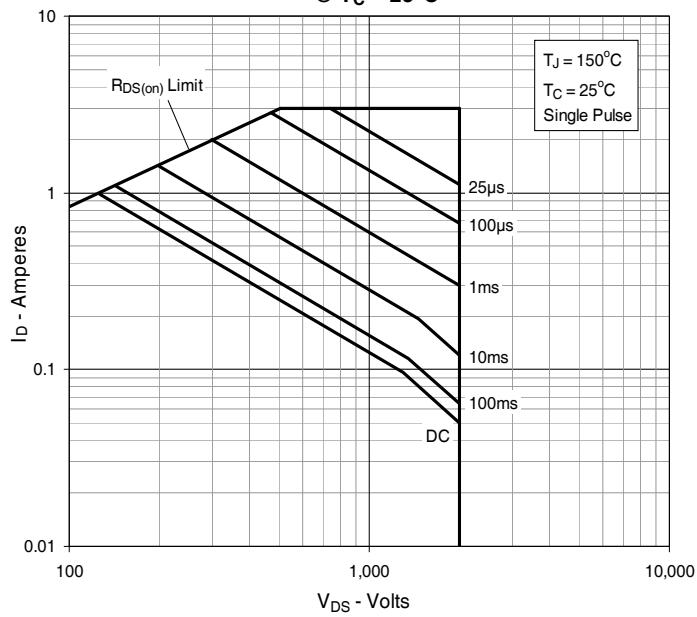
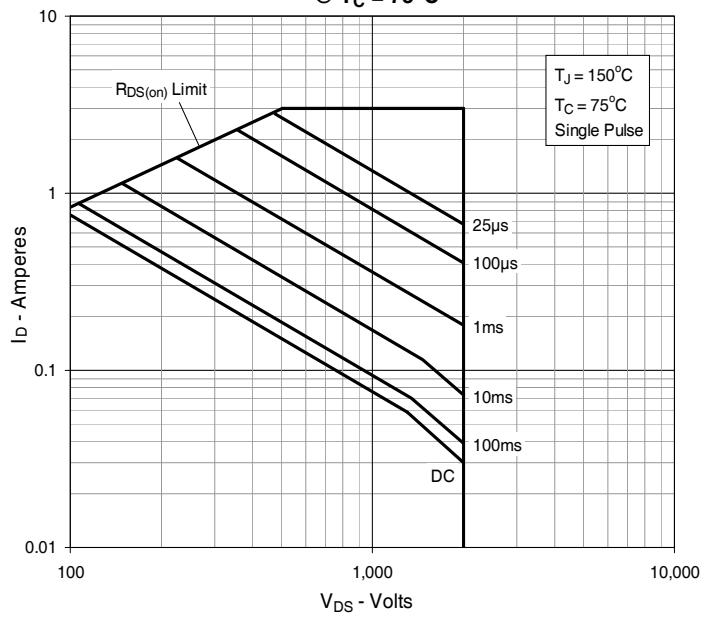
Fig. 7. Transconductance

Fig. 8. Forward Voltage Drop of Intrinsic Diode

Fig. 9. Gate Charge

Fig. 10. Capacitance

Fig. 11. Maximum Transient Thermal Impedance


Fig. 12. Forward-Bias Safe Operating Area

@ $T_C = 25^\circ\text{C}$

Fig. 13. Forward-Bias Safe Operating Area

@ $T_C = 75^\circ\text{C}$




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